

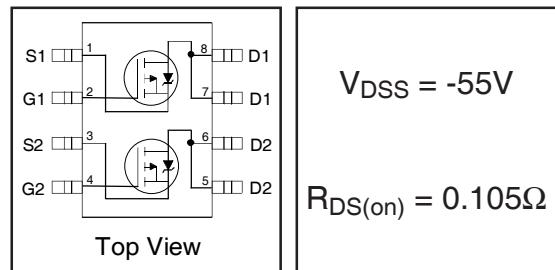
- Advanced Process Technology
- Ultra Low On-Resistance
- Dual P Channel MOSFET
- Surface Mount
- Available in Tape & Reel
- 150°C Operating Temperature
- Lead-Free

Description

These HEXFET® Power MOSFET's in a Dual SO-8 package utilize the lastest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of these HEXFET Power MOSFET's are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in a wide variety of other applications.

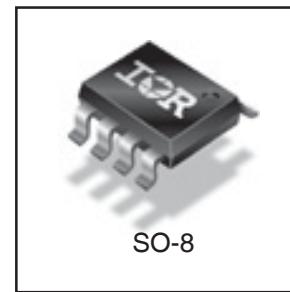
The efficient SO-8 package provides enhanced thermal characteristics and dual MOSFET die capability making it ideal in a variety of power applications. This dual, surface mount SO-8 can dramatically reduce board space and is also available in Tape & Reel.

HEXFET® Power MOSFET



$V_{DSS} = -55V$

$R_{DS(on)} = 0.105\Omega$



Base Part Number	Package Type	Standard Pack		Orderable Part Number	EOL Notice
		Form	Quantity		
IRF7342QPbF	SO-8	Tube/Bulk	95	IRF7342QPbF	EOL 529
IRF7342QPbF	SO-8	Tape and Reel	4000	IRF7342QTRPbF	

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain- Source Voltage	-55	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-3.4	A
$I_D @ T_C = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-2.7	
I_{DM}	Pulsed Drain Current ①	-27	
$P_D @ T_C = 25^\circ C$	Power Dissipation	2.0	W
$P_D @ T_C = 70^\circ C$	Power Dissipation	1.3	
	Linear Derating Factor	0.016	W/ $^\circ C$
V_{GS}	Gate-to-Source Voltage	± 20	V
V_{GSM}	Gate-to-Source Voltage Single Pulse $t_p < 10\mu s$	30	V
E_{AS}	Single Pulse Avalanche Energy ②	114	
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to + 150	$^\circ C$

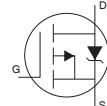
Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient ⑤	—	62.5	$^\circ C/W$

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	-55	—	—	V	$V_{\text{GS}} = 0\text{V}$, $I_D = -250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	-0.054	—	V°C	Reference to 25°C , $I_D = -1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.095	0.105	Ω	$V_{\text{GS}} = -10\text{V}$, $I_D = -3.4\text{A}$ ④
		—	0.150	0.170		$V_{\text{GS}} = -4.5\text{V}$, $I_D = -2.7\text{A}$ ④
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	-1.0	—	—	V	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = -250\mu\text{A}$
g_{fs}	Forward Transconductance	3.3	—	—	S	$V_{\text{DS}} = -10\text{V}$, $I_D = -3.1\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	-2.0	μA	$V_{\text{DS}} = -55\text{V}$, $V_{\text{GS}} = 0\text{V}$
		—	—	-25		$V_{\text{DS}} = -55\text{V}$, $V_{\text{GS}} = 0\text{V}$, $T_J = 55^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	$V_{\text{GS}} = -20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	100		$V_{\text{GS}} = 20\text{V}$
Q_g	Total Gate Charge	—	26	38	nC	$I_D = -3.1\text{A}$
Q_{gs}	Gate-to-Source Charge	—	3.0	4.5		$V_{\text{DS}} = -44\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	8.4	13		$V_{\text{GS}} = -10\text{V}$, See Fig. 10 ④
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	14	22	ns	$V_{\text{DD}} = -28\text{V}$
t_r	Rise Time	—	10	15		$I_D = -1.0\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	43	64		$R_G = 6.0\Omega$
t_f	Fall Time	—	22	32		$R_D = 16\Omega$, ④
C_{iss}	Input Capacitance	—	690	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	210	—		$V_{\text{DS}} = -25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	86	—		$f = 1.0\text{MHz}$, See Fig. 9

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	-2.0	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	-27		
V_{SD}	Diode Forward Voltage	—	—	-1.2	V	$T_J = 25^\circ\text{C}$, $I_S = -2.0\text{A}$, $V_{\text{GS}} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	54	80	ns	$T_J = 25^\circ\text{C}$, $I_F = -2.0\text{A}$
Q_{rr}	Reverse Recovery Charge	—	85	130	nC	$dI/dt = -100\text{A}/\mu\text{s}$ ③

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

③ $I_{\text{SD}} \leq -3.4\text{A}$, $dI/dt \leq -150\text{A}/\mu\text{s}$, $V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 150^\circ\text{C}$

② Starting $T_J = 25^\circ\text{C}$, $L = 20\text{mH}$
 $R_G = 25\Omega$, $I_{AS} = -3.4\text{A}$. (See Figure 8)

④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.

⑤ When mounted on 1 inch square copper board, $t < 10$ sec

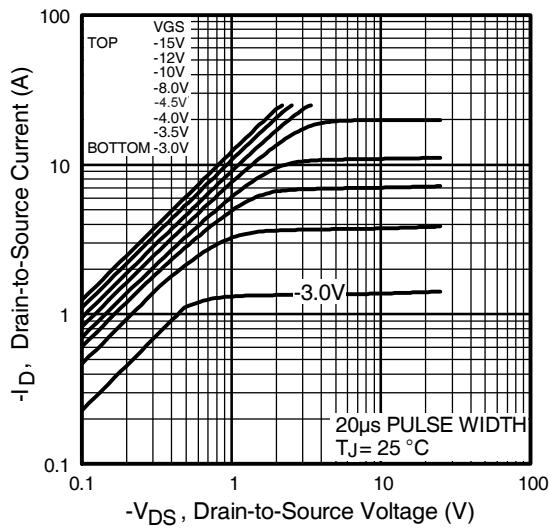


Fig 1. Typical Output Characteristics

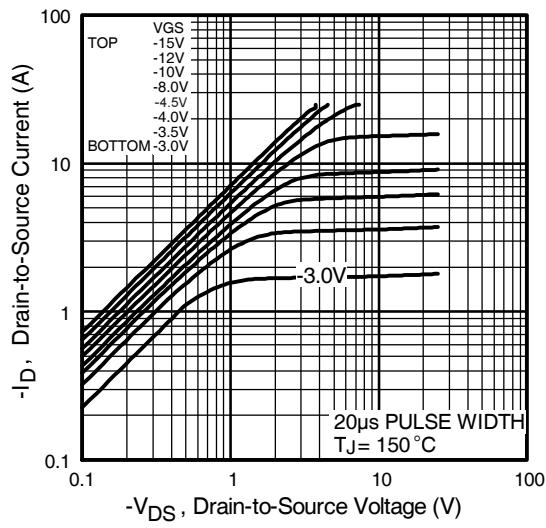


Fig 2. Typical Output Characteristics

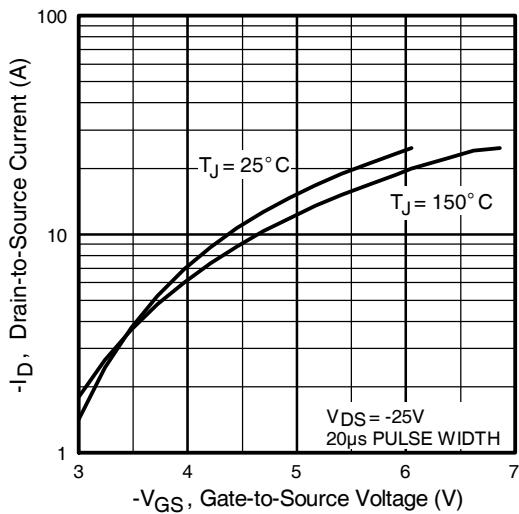


Fig 3. Typical Transfer Characteristics

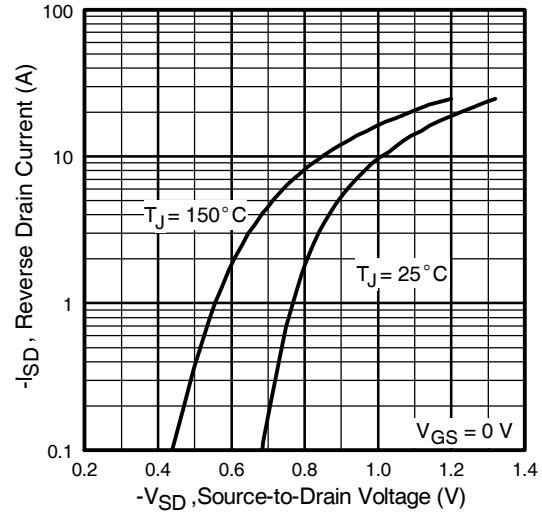


Fig 4. Typical Source-Drain Diode Forward Voltage

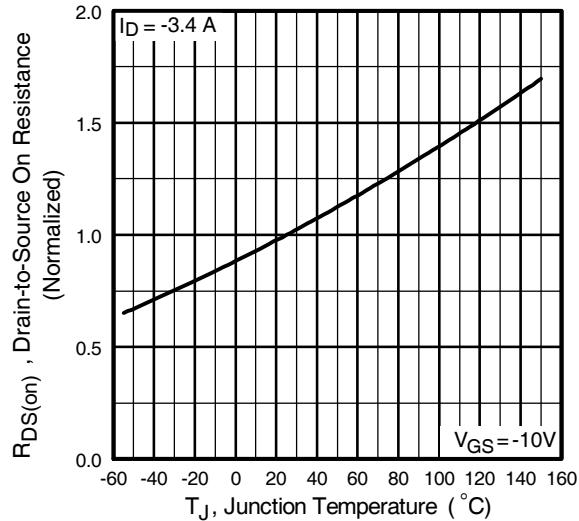


Fig 5. Normalized On-Resistance Vs. Temperature

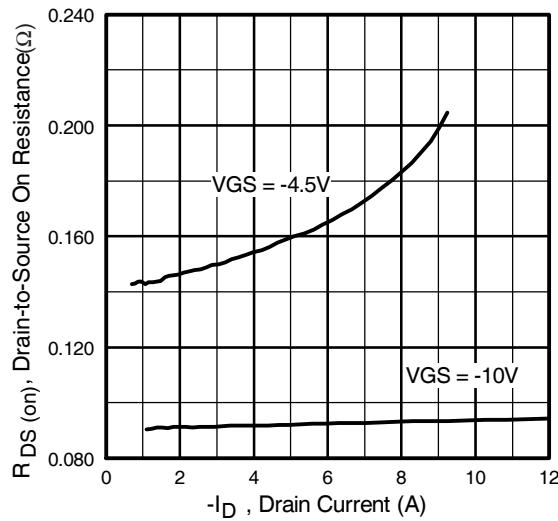


Fig 6. Typical On-Resistance Vs. Drain Current

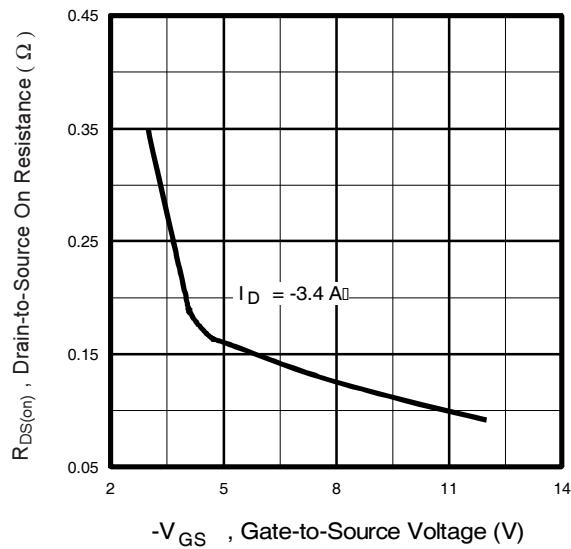


Fig 7. Typical On-Resistance Vs. Gate Voltage

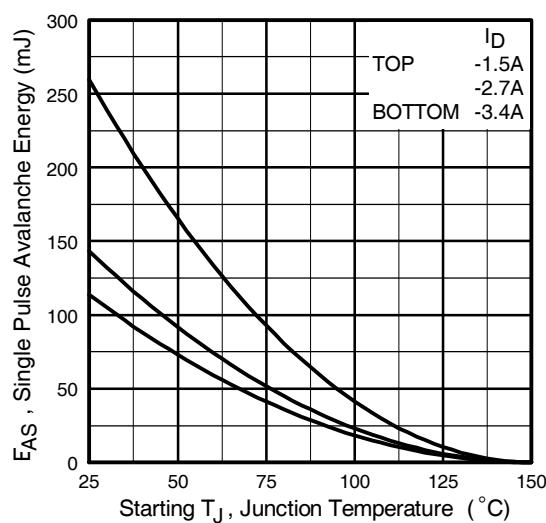


Fig 8. Maximum Avalanche Energy Vs. Drain Current

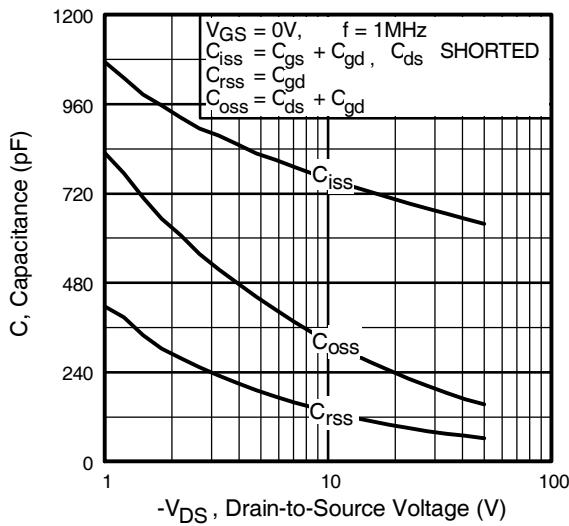


Fig 9. Typical Capacitance Vs.
Drain-to-Source Voltage

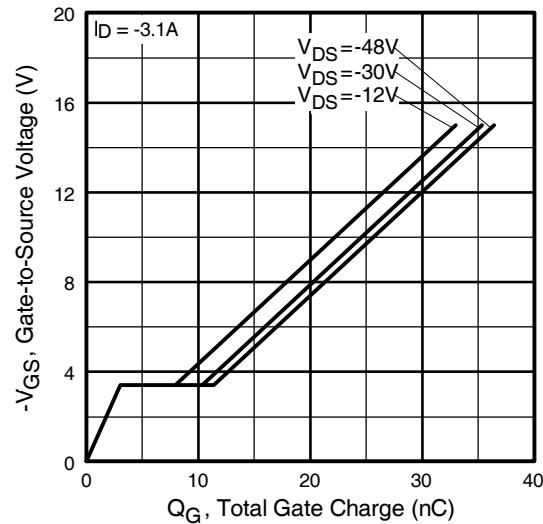


Fig 10. Typical Gate Charge Vs.
Gate-to-Source Voltage

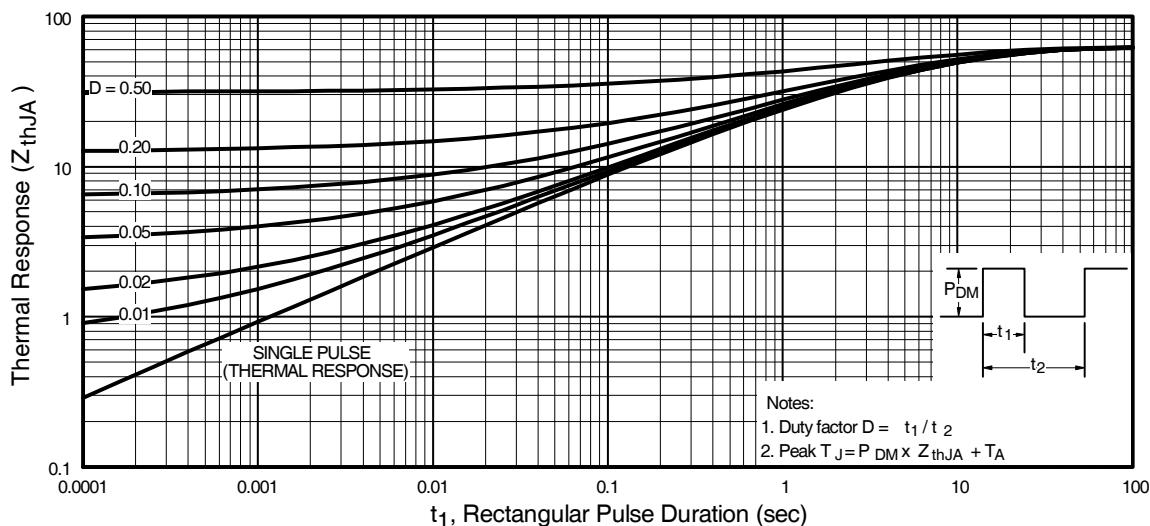
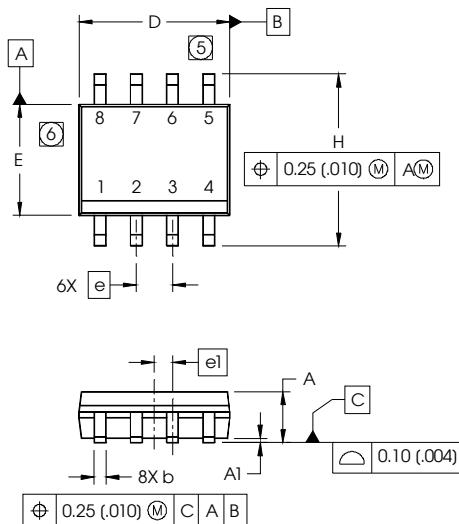


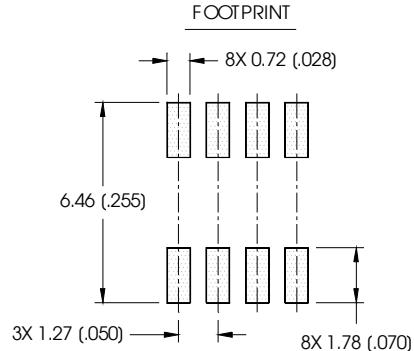
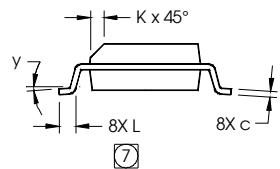
Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

SO-8 Package Outline

Dimensions are shown in millimeters (inches)

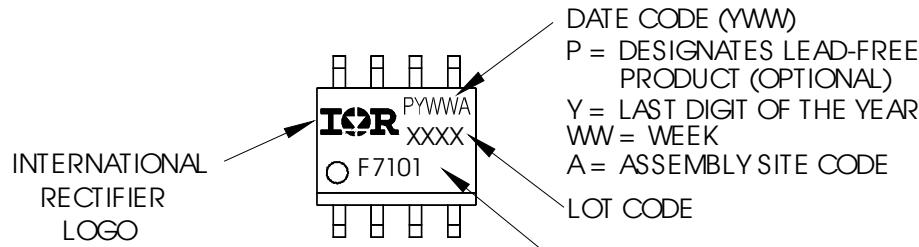


DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

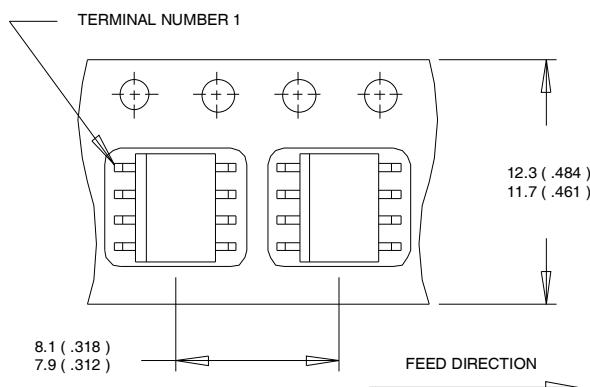


Note:

- For an Automotive Qualified version of this part please see : <http://www.irf.com/product-info/auto/>
- For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

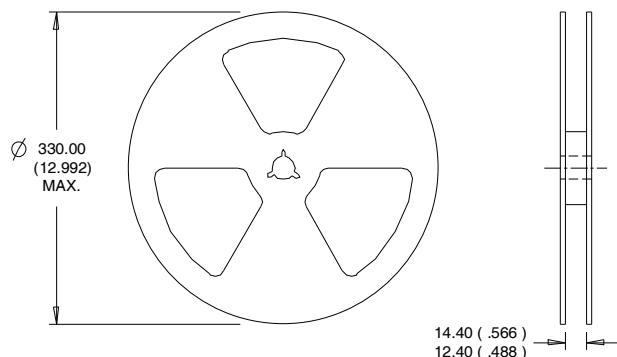
SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>



IRF7342QPbF

Qualification information[†]

Qualification level	Industrial (per JEDEC JESD47F ^{††} guidelines)	
Moisture Sensitivity Level	SO-8	MSL1 (per JEDEC J-STD-020D ^{††})
RoHS compliant	Yes	

[†] Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability>

^{††} Applicable version of JEDEC standard at the time of product release

Revision History

Date	Comment
8/22/2014	<ul style="list-style-type: none">• Updated data sheet based on corporate template.• Added Qual level on page 8.• Added ordering information and updated to reflect the End-Of-life (EOL) of the Tube option (EOL notice #529) on page1.

International
IR Rectifier

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